

Notice of References Cited	Application/Control No. 10/811,007		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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U.S. PATENT DOCUMENTS

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	U	"SAP Partnership", 2001 webpage of PMGBenchmarking.com, retrieved from http://web.archive.org/web/20010210225119/www.pmgbenchmarking.com/sap/sap_4.html
	V	Research in object-oriented manufacturing simulations: an assessment of the state of the art- S Narayanan, DA Bodner, T Govindaraj, LF ... - IIE transactions, 1998 - Springer
	W	PANEL SESSION: THE FUTURE OF SIMULATION BA Peters, JS Smith, DJ Medeiros, MW ... - Proceedings of the 2001 Winter Simulation Conference, 2001 - informs-sim.org
	X	Optimization of cycle time and utilization in semiconductor test manufacturing using simulation based, on-line, near-real-time scheduling system. AI Sivakumar - Simulation Conference Proceedings, 1999 Winter, 1999 - ieeexplore.ieee.org

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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